QUALIFICATION TEST REPORT

CONNECTOR, FPC, 1mm

501-278 Rev. O

Product Specification:	108-1393 Rev. O
CTL No.:	CTL4102-011-001
Date:	October 10, 1994
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(R4102TS)

AMP

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CORPORATE TEST LABORATORY

Qualification Test Report

1. Introduction

1.1 Purpose

Testing was performed on AMP* 1mm Flexible Printed Circuit (FPC) Connector to determine its conformance to the requirements of AMP Product Specification 108-1393 Rev. O.

1.2 Scope

This report covers the electrical, mechanical, and environmental performance of the 1mm FPC Connector manufactured by the Interconnection Components & Assemblies Product Division of the Capital Goods Business Unit. The testing was performed between August 8, 1994 and October 3, 1994.

1.3 Conclusion

The 1mm FPC Connector meets the electrical, mechanical, and environmental performance requirements of AMP Product Specification 108-1393 Rev. O.

* Trademark

1.4 Product Description

The 1mm FPC connector ranges in size from 4 to 30 positions. A single contact is produced with tails to provide right angle surface mount connections to a printed circuit board. An actuator provides Zero Insertion Forces (ZIF) action and the socket accepts Flexible Etched Cable (FEC), Flat Flexible Cable (FFC), or FPC.

1.5 Test Samples

The test samples were randomly selected from normal current production lots, and the following part numbers were used for test:

Test Group	Quantity	Part Nbr	Description
1,2,3,4	5	3-487951-0	30 Pos.Top Housing
1	10	487951-4	4 Pos. Top Housing
1,2,3,4	40	137009	FPC Cable

1.6 Qualification Test Sequence

	Test Groups			
Test or Examination	1	2	3	4
Examination of Product	1,7	1,7	1,8	1,3
Termination Resistance, Dry Circuit	2,6	2,6		
Dielectric Withstanding Voltage			3,7	
Insulation Resistance			2,6	
Vibration	4			
Physical Shock	5			
Contact Retention			9	
Durability	3	3		
Solderability				2
Thermal Shock			4	
Humidity-Temperature Cycling		4	5	
Temperature Life		5		

The numbers indicate sequence in which tests were performed.

2. Summary of Testing

2.1 Examination of Product - All Groups

All samples submitted for testing were selected from normal current production lots. They were inspected and accepted by the Product Assurance Department of the Capital Goods Business Unit.

2.2 Termination Resistance, Dry Circuit - Groups 1,2

All termination resistance measurements, taken at 100 milliamperes DC and 50 millivolts open circuit voltage, had a change in resistance (ΔR) of less than 10 milliohms after testing.

Test Group	Nbr of Data Points	Condition	Min	Max	Mean
1	60	After Mechanical	-3.42	+8.01	+1.570
2	30	After Environmental	+2.45	+9.07	+4.526

All values in milliohms

2.3 Dielectric Withstanding Voltage - Group 3

No dielectric breakdown or flashover occurred when a test voltage was applied between adjacent contacts.

2.3 Insulation Resistance - Group 3

All insulation resistance measurements were greater than 1,000 megohms.

2.4 Vibration - Group 1

No discontinuities of the contacts were detected during vibration. Following vibration, no cracks, breaks, or loose parts on the connector assemblies were visible.

2.5 Physical Shock - Group 1

No discontinuities of the contacts were detected during physical shock. Following physical shock testing, no cracks, breaks, or loose parts on the connector assemblies were visible.

2.6 Contact Retention - Group 3

No physical damage occurred to either the contacts or the housing, and no contacts dislodged from the housings as a result of supplying an axial load of 100 grams to the contacts.

2.7 Durability - Group 1

No physical damage occurred to the samples as a result of mating and unmating the connector 30 times.

2.8 Solderability - Group 4

The contact leads had a minimum of 95% solder coverage.

2.9 Thermal Shock - Group 3

No evidence of physical damage to either the contacts or the connector was visible as a result of thermal shock.

2.10 Humidity-Temperature Cycling - Groups 2,3

No evidence of physical damage to either the contacts or the connector was visible as a result of exposure to humidity-temperature cycling.

2.11 Temperature Life - Group 2

No evidence of physical damage to either the contacts or the connector was visible as a result of exposure to an elevated temperature.

3. Test Methods

3.1 Examination of Product

Product drawings and inspection plans were used to examine the samples. They were examined visually and functionally.

3.2 Termination Resistance, Low Level

Termination resistance measurements at low level current were made using a four terminal measuring technique (Figure 1). The test current was maintained at 100 milliamperes DC with an open circuit voltage of 50 millivolts DC.

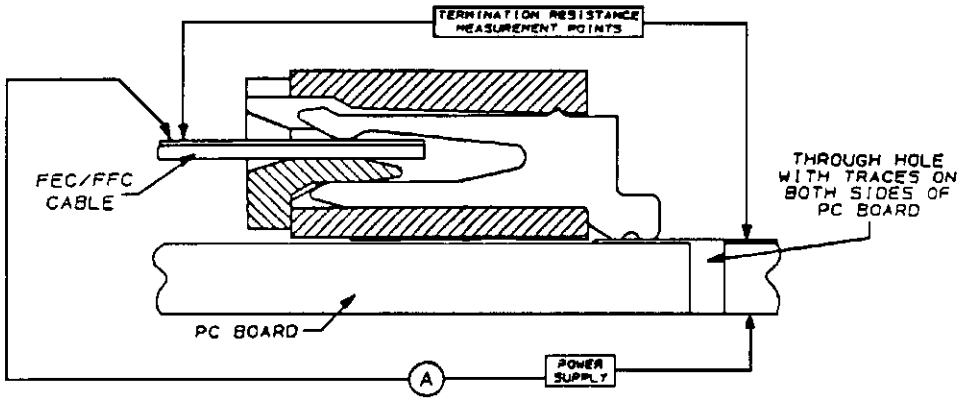

Figure 1
Typical Termination Resistance Measurement Points

3.3 Dielectric Withstanding Voltage

A test potential of 500 vac was applied between all adjacent contacts. This potential was applied for one minute and then returned to zero.

3.4 Insulation Resistance

Insulation resistance was measured between all adjacent contacts, using a test voltage of 500 volts DC. This voltage was applied for two minutes before the resistance was measured.

3.5 Vibration, Random

Mated connectors were subjected to a random vibration test, specified by a random vibration spectrum, with excitation frequency bounds of 50 and 2000 hertz. The power spectral density at 50 hz is 0.1 G^2/Hz. The spectrum slopes up at 6 dB per octave to a PSD of 0.4 G^2/Hz at 100 Hz. The spectrum is flat at 0.4 G^2/Hz from 100 to 1000 Hz. The spectrum slopes down at 6 dB per octave to the upper bound frequency of 2000 Hz, at which the PSD is 0.1 G^2/Hz. The root-mean square amplitude of the excitation was 23.91 GRMS. The connectors were monitored for discontinuities greater than one microsecond, using a current of 100 milliamperes in the monitoring circuit.

3.6 Physical Shock

Mated connectors were subjected to a physical shock test, having a sawtooth waveform of 100 gravity units (g peak) and a duration of 6 milliseconds. Three shocks in each direction were applied along the three mutually perpendicular planes, for a total of 18 shocks. The connectors were monitored for discontinuities greater than one microsecond, using a current of 100 milliamperes in the monitoring circuit.

3.7 Contact Retention

An axial load of 100 grams was applied to each contact and held for 60 seconds. The force was applied in a direction to cause removal of the contacts from the housing.

3.8 Durability

Connectors were mated and unmated 30 times.

3.9 Solderability

Connector assembly contact solder tails were subjected to a solderability test by immersing them in a nonactivated rosin flux for 5 to 10 seconds, allowed to drain for 10 to 60 seconds, then held over molten solder without contact for 2 seconds. The solder tails were then immersed in the molden solder at a rate of approximately one inch per second, held for 3 to 5 seconds, then withdrawn. After cleaning in isopropyl alcohol, the samples were visually examined for solder coverage. The solder used for testing was 60/40 tin lead composition and was maintained at a temperature of 245°C.

3.10 Thermal Shock

Mated connectors were subjected to 5 cycles of temperature extremes with each cycle consisting of 30 minutes at each temperature. The temperature extremes were -40°C and 85°C. The transition between temperatures was less than one minute.

3.11 Humidity-Temperature Cycling

Mated connectors were exposed to 10 cycles of humidity-temperature cycling. Each cycle lasted 24 hours and consisted of cycling the temperature between 25°C and 65°C twice while the relative humidity was held at 95%.

3.12 Temperature Life

Mated samples were exposed to a temperature of 85°C for 500 hours (21 days).

4. Validation

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